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Attorney Docket No.: 34592/US
Express Mail Label No.: EV 423 775 040 US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Fredrick W. Crist et al.

Appln. No.: 09/676,292

Filed: September 28, 2000

For: METHOD AND APPARATUS FOR REMOTELY
TESTING SEMICONDUCTORS

Confirmation No.: 2328

Group Art Unit: 2829

Examiner: Evan T. Pert

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
Under 37 C.F.R. § 1.97(c)(1), § 1.97(e)(1), and § 1.98

Sir:

The Examiner is requested to consider the references noted on the enclosed Form PTO-1449 during examination of the above-identified patent application. The references are submitted for the Examiner's consideration and are submitted pursuant to the duty of disclosure under 37 C.F.R. § 1.56. In submitting the references, no representation is made or implied that the references are or are not material to the examination of the application. The Examiner is encouraged to make his or her own determination of materiality. Copies of the cited documents are provided.

The references cited on the attached PTO-1449 were cited in an Office action dated April 22, 2004, of corresponding Japanese patent application No. 2001-287506, a copy of which is enclosed.

Japanese publication Nos. 06-120316; 11-015520; 10-256109; and 2000-077290 are not in the English language. Pursuant to 37 C.F.R. § 1.98(a)(3), any information disclosure statement filed under 37 C.F.R. § 1.97 shall include a concise explanation of the relevance, as it

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is presently understood by the individual designated in 37 C.F.R. § 1.56(c) most knowledgeable about the content of the information, of each patent, publication or other information listed that is not in the English language. The concise explanation may be either separate from the specification or incorporated therein. English translations of the abstracts (from the Japanese Patent Office) are attached to the Japanese references, which are enclosed to satisfy the requirement for a concise explanation of relevance under 37 C.F.R. § 1.98(a)(3).

Statement Under 37 C.F.R. § 1.97(e)(1)

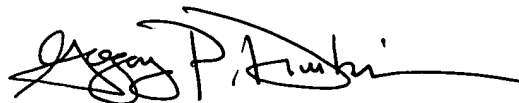
The undersigned hereby certifies that the references cited on the attached PTO-1449 were cited in a communication from a foreign patent office in a corresponding foreign application not more than three months prior to the filing of this information disclosure statement.

Pursuant to 37 C.F.R. § 1.97(c)(1) and § 1.97(e)(1), no fees are due with respect to this filing. However, should any fees be deemed necessary, such fees may be charged to Deposit Account No. 04-1415.

If the examiner has any questions, please contact the undersigned attorney.

Dated: 12 July 2004.

Respectfully submitted,



Gregory P. Durbin, Reg. No. 42,503
DORSEY & WHITNEY LLP
370 Seventeenth Street, Suite 4700
Denver, CO 80202-5647
Tel.: (303) 629-3400
Fax: (303) 629-3450

USPTO Customer No. 20686

Enclosures



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Alexandria, VA 22313-1450

Sir:

The undersigned hereby certifies that the following documents:

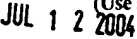
1. Supplemental Information Disclosure Statement Under 37 C.F.R. § 1.97(c)(1), § 1.97(e)(1), and § 1.98;
2. Information Disclosure Statement by Applicant (Form PTO-1449);
3. Four (4) references;
4. Photocopy of Office action dated April 22, 2004, of corresponding Japanese patent application No. 2001-287506, including English translation thereof;
5. Certificate of Mailing by Express Mail; and
6. Return Card,

relating to the above application, were deposited as "Express Mail," under 37 C.F.R. § 1.10, Mailing Label No. EV 423 775 040 US with the United States Postal Service, addressed to Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 12 day of July 2004.

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**GROUP
2829**



U.S. PATENT DOCUMENTS

[illegible]**FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION**[illegible]

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.